



IPAD™

## EMIF10-LCD01F1

### 10 LINES EMI FILTER AND ESD PROTECTION

#### MAIN PRODUCT CHARACTERISTICS:

Where EMI filtering in ESD sensitive equipment is required :

- LCD for Mobile phones
- Computers and printers
- Communication systems
- MCU Boards

#### DESCRIPTION

The EMIF10-LCD01F1 is a 10 lines highly integrated devices designed to suppress EMI/RFI noise in all systems subjected to electromagnetic interferences. The EMIF10 flip chip packaging means the package size is equal to the die size. This filter includes an ESD protection circuitry, which prevents the device from destruction when subjected to ESD surges up 15kV.

#### BENEFITS

- EMI symmetrical (I/O) low-pass filter
- High efficiency in EMI filtering
- Very low PCB space consuming:  
2.64mm x 2.64mm
- Very thin package: 0.65 mm
- High efficiency in ESD suppression on input pins (IEC6100-4-2 level 4)
- High reliability offered by monolithic integration
- High reducing of parasitic elements through integration & wafer level packaging.

#### COMPLIES WITH THE FOLLOWING STANDARDS:

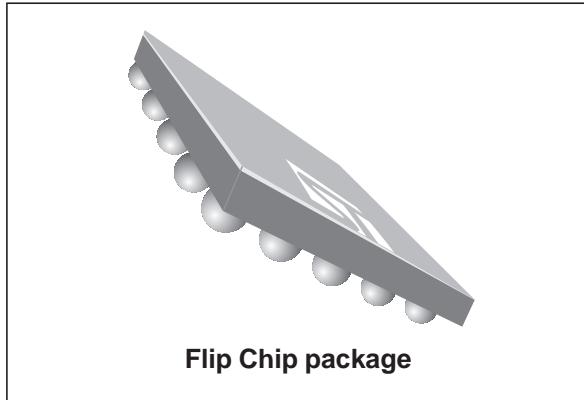
##### IEC61000-4-2

Level 4 input pins 15kV (air discharge)  
8 kV (contact discharge)

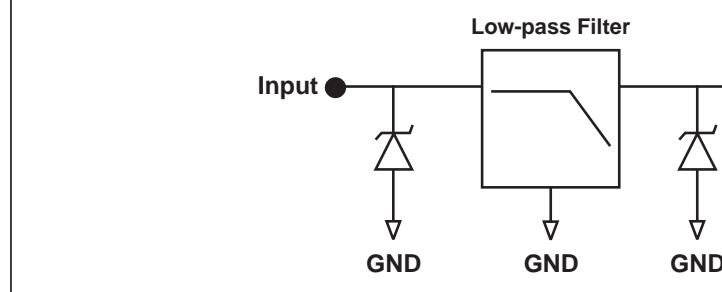
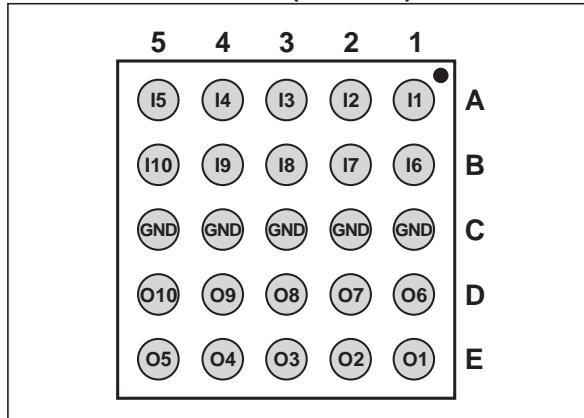
Level 1 output pins 2kV (air discharge)  
2kV (contact discharge)

##### MIL STD 883E - Method 3015-6 Class 3

#### BASIC CELL CONFIGURATION



#### PIN CONFIGURATION (ball side)



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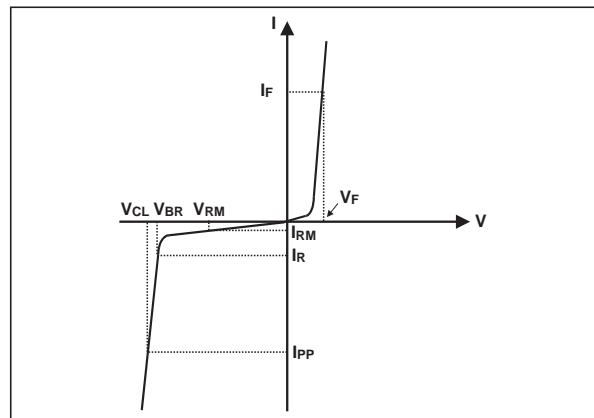
## EMIF10-LCD01F1

### ABSOLUTE MAXIMUM RATINGS ( $T_{amb} = 25^{\circ}\text{C}$ )

| Symbol    | Parameter and test conditions | Value       | Unit               |
|-----------|-------------------------------|-------------|--------------------|
| $T_j$     | Maximum junction temperature  | 125         | $^{\circ}\text{C}$ |
| $T_{op}$  | Operating temperature range   | -40 to +85  | $^{\circ}\text{C}$ |
| $T_{stg}$ | Storage temperature range     | -55 to +150 | $^{\circ}\text{C}$ |

### ELECTRICAL CHARACTERISTICS ( $T_{amb} = 25^{\circ}\text{C}$ )

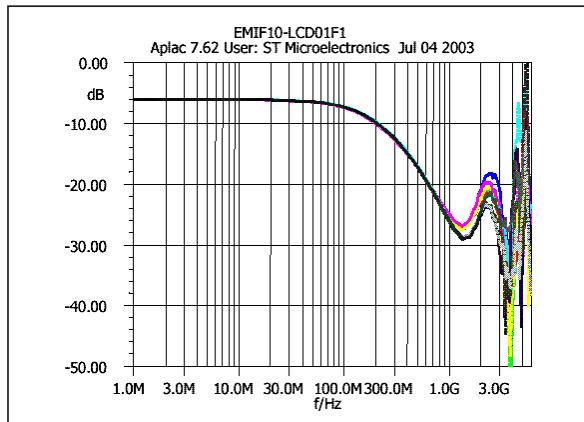
| Symbol     | Parameters                               |
|------------|--|
| $V_{BR}$   | Breakdown voltage                        |
| $I_{RM}$   | Leakage current @ $V_{RM}$               |
| $V_{RM}$   | Stand-off voltage                        |
| $V_{CL}$   | Clamping voltage                         |
| $R_d$      | Dynamic impedance                        |
| $I_{PP}$   | Peak pulse current                       |
| $R_{I/O}$  | Series resistance between Input & Output |
| $C_{line}$ | Input capacitance per line               |



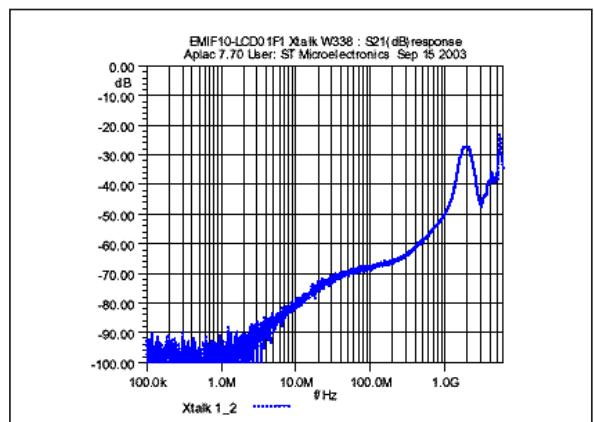
| Symbol     | Test conditions  | Min | Typ              | Max | Unit     |
|------------|--|-----|------------------|-----|----------|
| $V_{BR}$   | $I_R = 1\text{mA}$   | 6   | 8                | 10  | V        |
| $I_{RM}$   | $V_{RM} = 3\text{V}$   |     |                  | 500 | nA       |
| $R_{I/O}$  |  | 90  | 100              | 110 | $\Omega$ |
| $C_{line}$ | At 0V bias   |     |                  | 35  | pF       |
| $Rt / Ft$  | Induced rise and fall time 10-90% at 26 MHz frequency signal $V = 1.9\text{V}$ ( $Rt / Ft$ input 1 ns, $50\Omega$ impedance generator) |     | 8 <sup>(1)</sup> |     | ns       |

(1) guaranteed by design

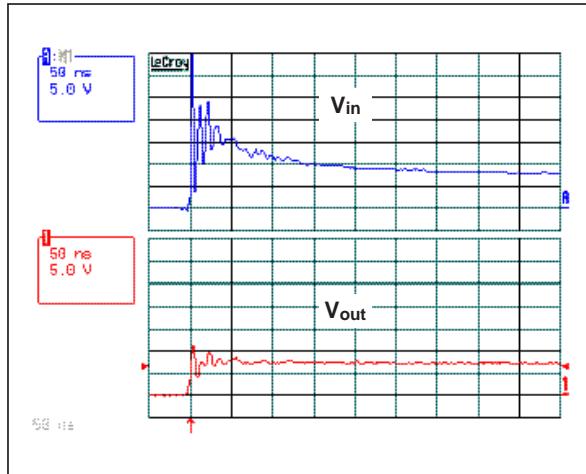
**Fig. 1:** S21(dB) all lines attenuation measurement and Aplac simulation.



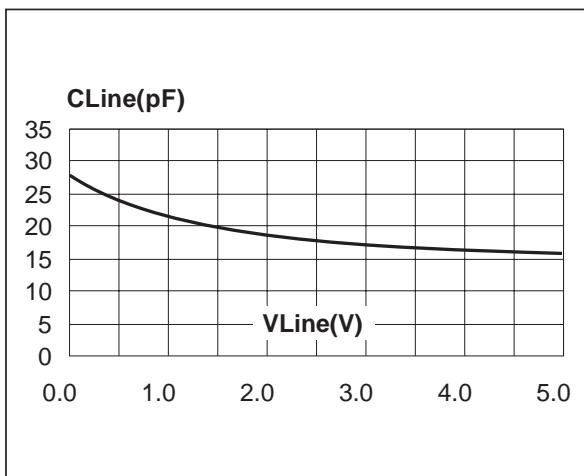
**Fig. 2:** Analog crosstalk measurements.



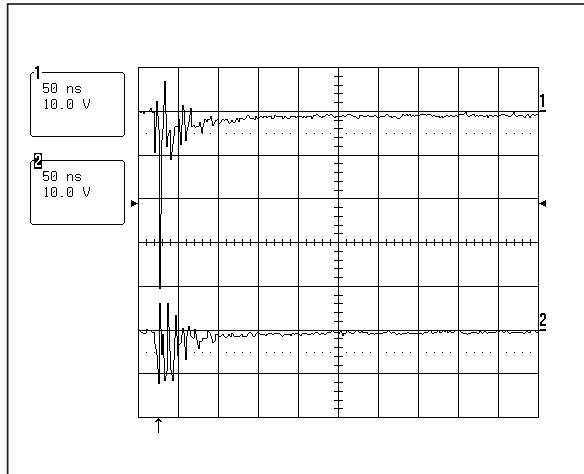
**Fig. 3:** ESD response to IEC61000-4-2 (+15kV air discharge) on one input and one output.



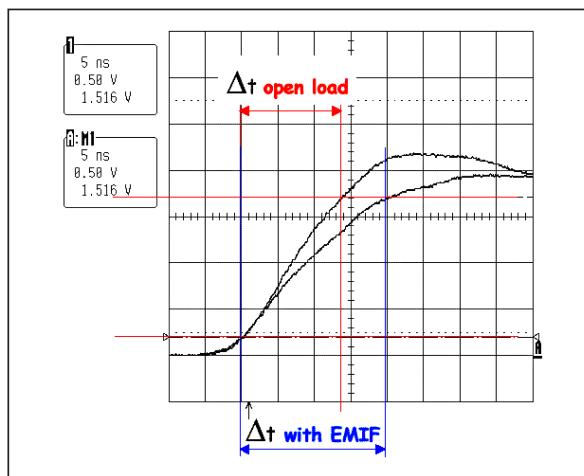
**Fig. 5:** Line capacitance versus applied voltage.



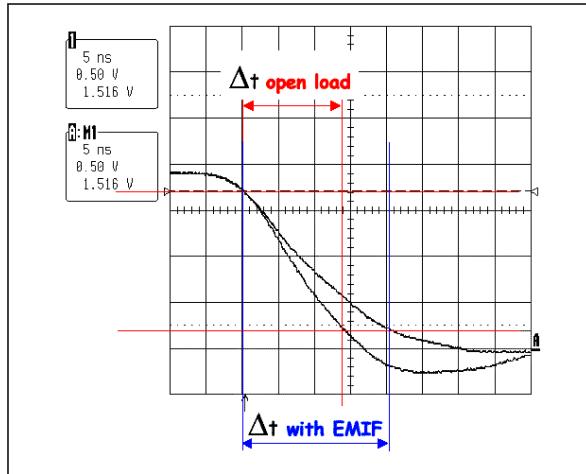
**Fig. 4:** ESD response to IEC61000-4-2 (-15kV air discharge) on one input and one output.



**Fig. 6:** Rise time 10-90% measurements with 1.9V signal at 26 MHz frequency (50Ω generator).

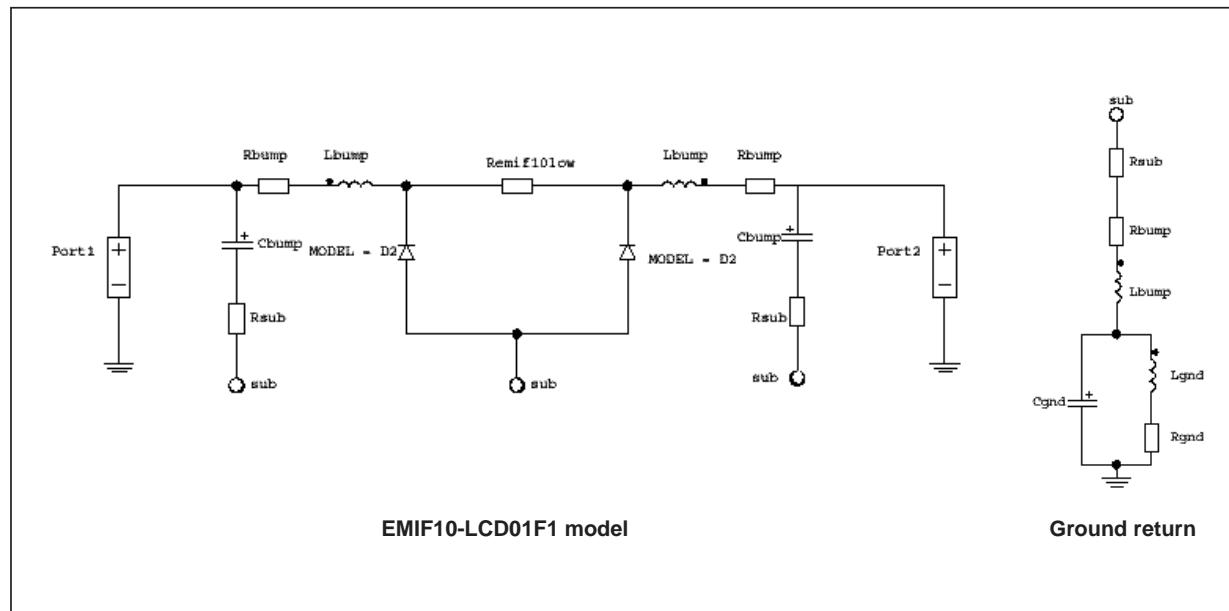


**Fig. 7:** Fall time 10-90% measurements with 1.9V signal at 26 MHz frequency (50Ω generator).



## EMIF10-LCD01F1

### Aplac model.

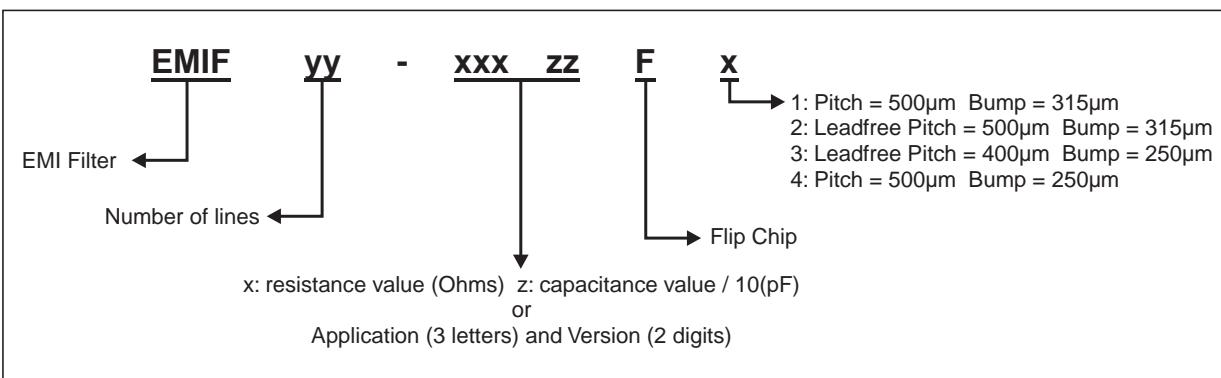


### Aplac parameters.

ZRZ structure  
 aplacvar Remif10low 100  
 aplacvar Cemif10flow 17.5pF  
 Bumps  
 aplacvar Lbump 50pH  
 aplacvar Rbump 20m  
 aplacvar Cbump 1.5pF  
 Bulk  
 aplacvar Rsub 100m  
 Gnd connections  
 aplacvar Rgnd 100m  
 aplacvar Lgnd 200pH  
 aplacvar Cgnd 0.15pF

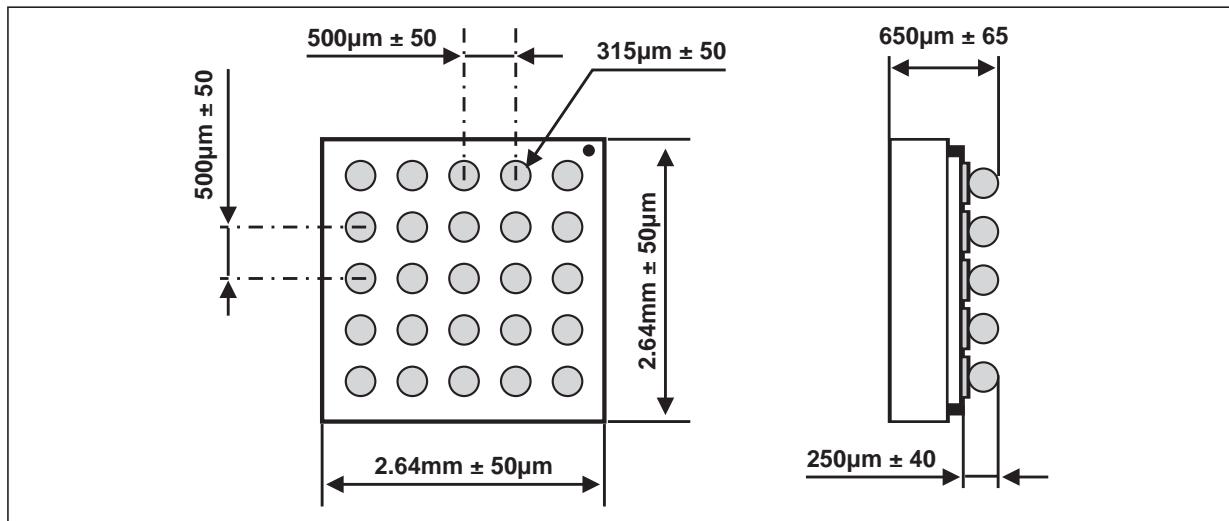
BV = 7  
 CJO = Cemif10low  
 IBV = 1u  
 IKF = 1000  
 IS = 10f  
 ISR = 100p  
 N = 1  
 M = 0.3333  
 RS = 0.015  
 VJ = 0.6  
 TT = 50n

### ORDER CODE

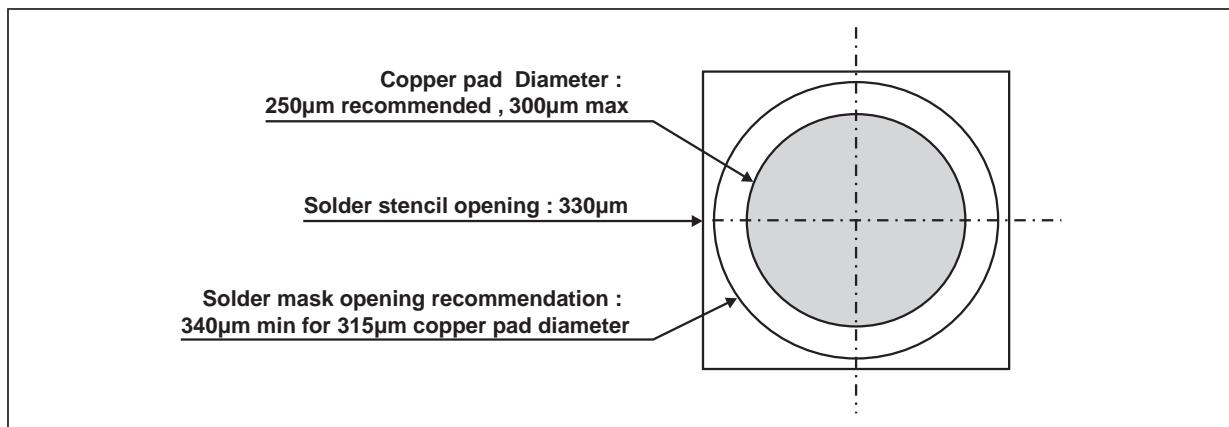


## PACKAGE MECHANICAL DATA

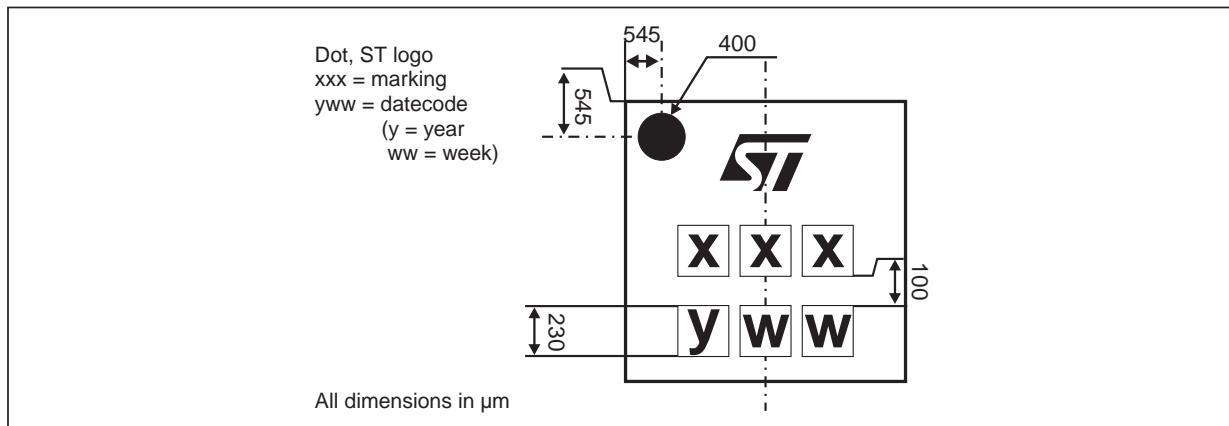
### FLIP CHIP



## FOOT PRINT RECOMMENDATIONS

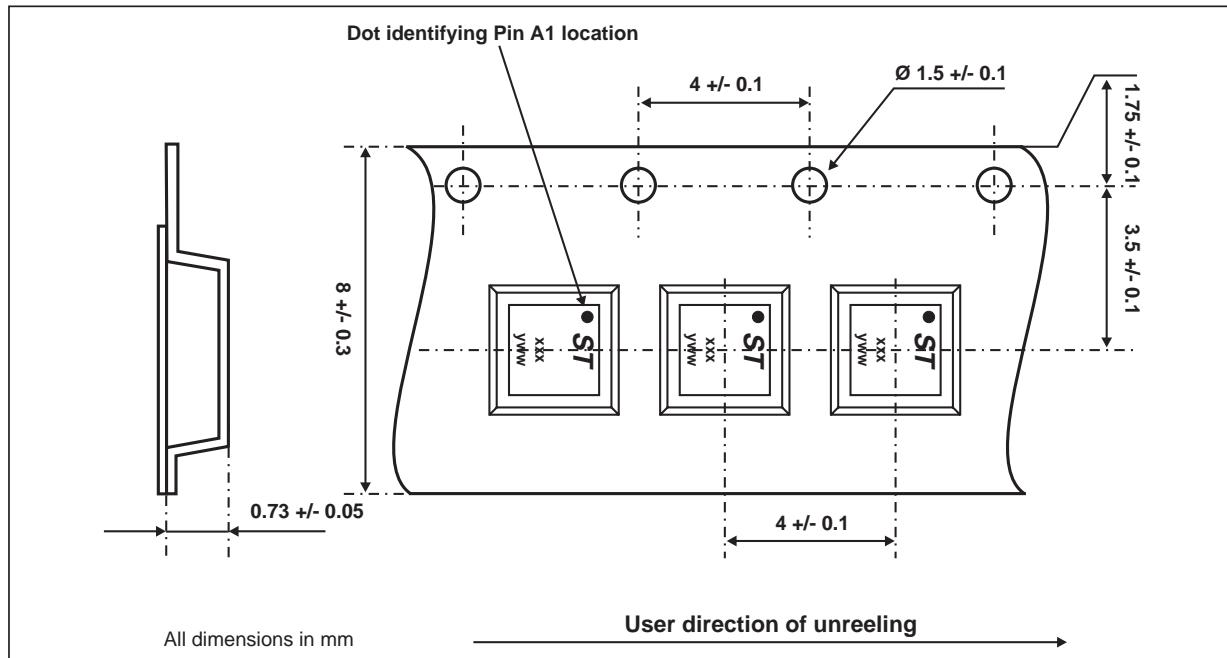


## MARKING



## EMIF10-LCD01F1

### PACKING



### OTHER INFORMATION

| Ordering code  | Marking | Package   | Weight | Base qty | Delivery mode    |
|----------------|---------|-----------|--------|----------|------------------|
| EMIF10-LCD01F1 | FLT     | Flip Chip | 9.3 mg | 5000     | Tape & reel (7") |

**Note:** More information are available in the application notes:

- AN1235: "Flip-Chip: Package description and recommandations for use"
- AN1751: "EMI Filters: Recommendations and measurements"

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